

Search Notes

Application/Control No.

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Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

PUPPO ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update keywords search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	4/11/2006	BT